



IEEE Instrumentation and Measurement Technology Conference (IMTC/2003)

Instrumentation and Measurement at the Summit

Vail Cascade Hotel Vail, Colorado, USA 20-22 May, 2003 (Tuesday-Thursday)

Call for Papers

The conference studies all aspects of instrumentation, measurement and control technologies - theory, research and development and applications. Program topics include the full spectrum of measurements:

A/D, D/A and Data Acquisition
Analog, Digital and Mixed Signal Processing
Automated Test and Measurement Systems
Calibration, Metrology and Standards
Computer Network Measurements
Dielectric and Magnetic Material Measurements
Distributed Measurement and Control
Embedded Information Systems
Embedded Sensors
EMC Instrumentation and Measurement
Fault Tolerance, Testing and Diagnosis
High Resolution Imaging
Imaging Systems and Image Reconstruction
Integrated Measurement Systems
Integrated Smart Sensors and Sensor Fusion

Intelligent Computing and Emerging Technologies
Inverse Scattering
Instrumentation and Prototype Development
Moisture Measurement and Instrumentation
Near-Field Imaging
Non-Invasive Instrumentation and Measurement
Self-Test, Self-Diagnostics and Self-Calibration
Sensors and Transducers
Sensing and Networking
System Identification and Control
Virtual Measurement Systems
Waveform Measurement and Analysis
Emerging Instrumentation and Measurement Technologies

Authors should submit electronically one copy of an extended abstract (three or four pages) *in English only*, reflecting new or advanced study, theory or application and including the significance of the contribution, a list of references and figures or tables. Abstracts must be prepared according to the Abstract Preparation Guide and must be accompanied by an Abstract Submission Form. Both documents may be downloaded from the IMTC website – <http://www.ieee-imtc.org> Check the website for all instructions and details. .

Important dates for authors:

- **15 October 2002** – Abstract submission deadline – submit to lee.myers@ieee.org
- **18 December 2002** – Author notification of acceptance or rejection
- **3 March 2003** – Deadline for receipt of final manuscript

Papers will be reviewed by the IMTC International Program Committee. Authors of accepted abstracts must guarantee they will register at the conference, pay registration fees, attend and present their papers. An accepted paper will be published in the proceedings only if the final manuscript is accompanied by registration form(s) and fee(s) for at least one of the authors (only full member or non-member fees will be allowed – *no exceptions!*) One author registration will guarantee publication of up to two accepted papers; each additional accepted paper with the same registration will require a printing contribution of \$50. Authors of presented papers are invited to submit extended manuscripts to the special IMTC/2003 issue of the *IEEE Transactions on Instrumentation and Measurement*, to be published in 2004.

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